

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Yutaka YONEDA et al.
International Application No.: PCT/JP03/15894
International Filing Date: December 11, 2003
For: PIXEL DEFECT DETECTING AND CORRECTING
APPARATUS AS WELL AS PIXEL DEFECT
DETECTING AND CORRECTING METHOD

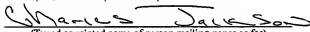
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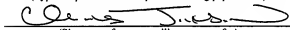
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Sir:

Enclosed are copies of the publications, which were cited in the International Search Report of International Application No. PCT/JP03/15894. Also enclosed is a copy of Form PTO-1449 and the International Search Report.

In the event the above-identified patent application was filed after June 30, 2003 or is an international application that entered the national stage under 35 U.S.C. 371 after June

30, 2003, no copy of any cited U.S. patent or U.S. patent application publication is provided.

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REMARKS

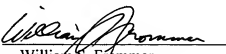
Entry of this Information Disclosure Statement and an early examination on the merits are respectfully solicited.

Please charge any additional fees to Deposit Account No. 50-0320.

Respectfully submitted,

FROMMER LAWRENCE & HAUG LLP
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Enclosures

Based on Form PTO-1449 (3/90)	ATTY. DOCKET NO. 450100-04854	RECEIVED 10/25/05 Filed Concurrently Herewith
	LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	
	APPLICANT Yutaka YONEDA et al.	FILING DATE Filed Concurrently Herewith
		GROUP

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AL	JP 2002-271806	09/20/02	Japan			
	AM	JP 10-243300	09/11/98	Japan			
	AN	JP 2001-54127	02/23/01	Japan			
	AO	JP 2003-158744	05/30/03	Japan			
	AP						

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AQ						
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EXAMINER /Timothy Henn/	DATE CONSIDERED 10/01/2008
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